

Miroslav Valtr

List of Publications by Year in descending order

Source: <https://exaly.com/author-pdf/6046225/publications.pdf>

Version: 2024-02-01

10
papers

96
citations

1478505

6
h-index

1372567

10
g-index

10
all docs

10
docs citations

10
times ranked

123
citing authors

#	ARTICLE	IF	CITATIONS
1	Large area high-speed metrology SPM system. <i>Nanotechnology</i> , 2015, 26, 065501.	2.6	27
2	Gwyscan: a library to support non-equidistant scanning probe microscope measurements. <i>Measurement Science and Technology</i> , 2017, 28, 034015.	2.6	21
3	Rough surface scattering simulations using graphics cards. <i>Applied Surface Science</i> , 2010, 256, 5640-5643.	6.1	10
4	Estimation of roughness measurement bias originating from background subtraction. <i>Measurement Science and Technology</i> , 2020, 31, 094010.	2.6	10
5	Near-field optical microscopy simulations using graphics processing units. <i>Surface and Interface Analysis</i> , 2010, 42, 1109-1113.	1.8	9
6	Interplay between multipole expansion of exchange interaction and Coulomb correlation of exciton in colloidal II-VI quantum dots. <i>Electronic Structure</i> , 2022, 4, 015006.	2.8	6
7	Large area scanning thermal microscopy and infrared imaging system. <i>Measurement Science and Technology</i> , 2019, 30, 035010.	2.6	5
8	Design and performance of a test rig for evaluation of nanopositioning stages. <i>Measurement Science and Technology</i> , 2019, 30, 035002.	2.6	4
9	GSvit – An open source FDTD solver for realistic nanoscale optics simulations. <i>Computer Physics Communications</i> , 2021, 265, 108025.	7.5	3
10	Multiple-fibre interferometry setup for probe sample interaction measurements in atomic force microscopy. <i>Measurement Science and Technology</i> , 2020, 31, 094001.	2.6	1